

4/16/2014



**RELIABILITY MONITOR REPORT  
FOR**

**X3 MBiC3 SiGe HBT 0.35μm (MB3)**

**MAXIM INTEGRATED**

**160 RIO ROBLES  
SAN JOSE, CA 95134**

**This Report was prepared by  
MAXIM INTEGRATED Reliability Engineering**

**Summary:**

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX2832ETM+	MAX3521ETP+
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The calculated failure rate for devices using this process is:

**FAILURE RATE:    MTTF (YRS): 6251    QUANTITY: 180    FAILS: 0    FITS: 18.3**

The parameters used to calculate this failure rate are as follows:

**Cf: 60%                    Ea: 0.7                    Tu: 25    °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2013 and 3/31/2014 .

**Process Information:**

Process Description:            X3 MBiC3 SiGe HBT 0.35µm (MB3)

**OPERATING LIFE**

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1303	MAX2832ETM+	135°C	192 HRS	70	0	STB3NA291DQ
HIGH TEMP OP LIFE	1316	MAX3521ETP+	135°C	192 HRS	80	0	SAML3Q002BQ
HIGH TEMP OP LIFE	1316	MAX3521ETP+	135°C	192 HRS	30	0	SAML3Q002CQ
<b>Total:</b>						<b>0</b>	

**FAILURE RATE:    MTTF (YRS): 6251    QUANTITY: 180    FAILS: 0    FITS: 18.3**